Search Notes



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10584956

Applicant(s)/Patent Under Reexamination

BAKER ET AL.

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DAVID Q NGUYEN

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Class	Subclass	Date	Examiner
370	312	02/18/2010	DN
375	329	02/18/2010	DN
375	279	02/18/2010	DN
375	280	02/18/2010	DN

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